

# SU6012V GaN TRANSISTOR

Document Number: SU6012V  
Preliminary Datasheet V2.0

## Gallium Nitride 50V 120W, RF Power Transistor

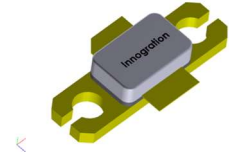
### Description

The SU6012V is a 120W single ended, input matched GaN HEMT, designed for multiple applications with frequencies up to 4GHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical performance (on Innogration 1.8-4.0GHz class AB fixture with device soldered)

### SU6012V



| SU6012V Vgs=-2.95V Vds=50V Idq=100mA CW |            |          |         |           |           |        |
|---|------------|----------|---------|-----------|-----------|--------|
| Freq (MHz)                              | Psat (dBm) | Psat (W) | IDS (A) | Pin (dBm) | Gain (dB) | Eff(%) |
| 1800                                    | 50.21      | 105.0    | 4.51    | 38.98     | 11.23     | 46.54  |
| 2000                                    | 49.54      | 89.9     | 3.45    | 37.87     | 11.67     | 52.14  |
| 2100                                    | 49.23      | 83.8     | 3.26    | 38.08     | 11.15     | 51.38  |
| 2200                                    | 49.93      | 98.4     | 3.56    | 39.57     | 10.36     | 55.28  |
| 2300                                    | 49.41      | 87.3     | 3.22    | 38.94     | 10.47     | 54.22  |
| 2400                                    | 49.88      | 97.3     | 3.96    | 39.63     | 10.25     | 49.13  |
| 2500                                    | 49.67      | 92.7     | 4.32    | 39.51     | 10.16     | 42.91  |
| 2600                                    | 50.70      | 117.5    | 5.30    | 41.65     | 9.05      | 44.34  |
| 2700                                    | 50.80      | 120.2    | 5.05    | 40.80     | 10.00     | 47.61  |
| 2800                                    | 50.52      | 112.7    | 4.94    | 40.56     | 9.96      | 45.64  |
| 2900                                    | 50.35      | 108.4    | 4.87    | 41.10     | 9.25      | 44.51  |
| 3000                                    | 50.08      | 101.9    | 4.70    | 40.43     | 9.65      | 43.34  |
| 3100                                    | 50.24      | 105.7    | 4.63    | 40.74     | 9.50      | 45.65  |
| 3200                                    | 50.21      | 105.0    | 4.52    | 40.96     | 9.25      | 46.44  |
| 3300                                    | 50.34      | 108.1    | 4.61    | 40.87     | 9.47      | 46.92  |
| 3400                                    | 50.10      | 102.3    | 4.38    | 40.91     | 9.19      | 46.73  |
| 3500                                    | 50.31      | 107.4    | 4.58    | 41.06     | 9.25      | 46.90  |
| 3600                                    | 50.35      | 108.4    | 4.62    | 40.82     | 9.53      | 46.92  |
| 3700                                    | 49.94      | 98.6     | 4.54    | 39.86     | 10.08     | 43.45  |
| 3800                                    | 50.14      | 103.3    | 4.64    | 40.01     | 10.13     | 44.52  |
| 3900                                    | 49.83      | 96.2     | 4.35    | 38.73     | 11.10     | 44.21  |
| 4000                                    | 49.36      | 86.3     | 3.76    | 37.86     | 11.50     | 45.90  |

### Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

### Important Note: Proper Biasing Sequence for GaN HEMT Transistors

#### Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (50V)

#### Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V

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3. Increase VGS until IDS current is attained

4. Apply RF input power to desired level
3. Reduce VDS down to 0 V

4. Turn off VGS

Table 1. Maximum Ratings

| Rating                         | Symbol   | Value       | Unit |
|--------------------------------|----------|-------------|------|
| Drain--Source Voltage          | $V_{DS}$ | +200        | Vdc  |
| Gate--Source Voltage           | $V_{GS}$ | -8 to 0     | Vdc  |
| Operating Voltage              | $V_{DD}$ | 0 to 55     | Vdc  |
| Maximum forward gate current   | $I_{gf}$ | 16          | mA   |
| Storage Temperature Range      | Tstg     | -65 to +150 | C    |
| Case Operating Temperature     | $T_C$    | -55 to +150 | C    |
| Operating Junction Temperature | $T_J$    | +225        | C    |

Table 2. Thermal Characteristics

| Characteristic   | Symbol          | Value | Unit |
|--|-----------------|-------|------|
| Thermal Resistance, Junction to Case<br>$T_C=85^{\circ}\text{C}$ , $T_J=200^{\circ}\text{C}$ , DC Power Dissipation, FEA | $R_{\theta JC}$ | 2     | C/W  |

Table 3. Electrical Characteristics ( $T_C = 25^{\circ}\text{C}$  unless otherwise noted)

DC Characteristics

| Characteristic                 | Conditions   | Symbol       | Min | Typ   | Max | Unit |
|--------------------------------|--|--------------|-----|-------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS}=-8\text{V}$ ; $I_{DS}=16\text{mA}$                                   | $V_{DSS}$    |     | 200   |     | V    |
| Gate Threshold Voltage         | $V_{DS}=50\text{V}$ , $I_D=16\text{mA}$                                      | $V_{GS(th)}$ | -4  |       | -2  | V    |
| Gate Quiescent Voltage         | $V_{DS}=50\text{V}$ , $I_{DS}=100\text{mA}$ ,<br>Measured in Functional Test | $V_{GS(Q)}$  |     | -3.04 |     | V    |

## Reference Circuit of Test Fixture Assembly Diagram

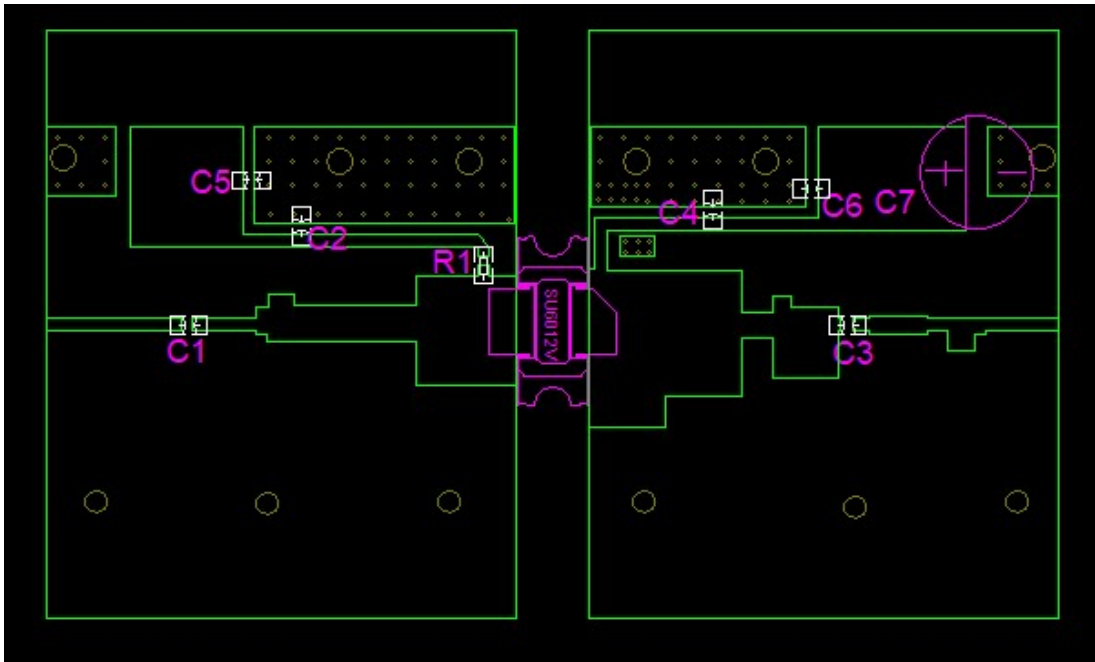


Figure 1. Test Circuit Component Layout (1800-4000MHz)

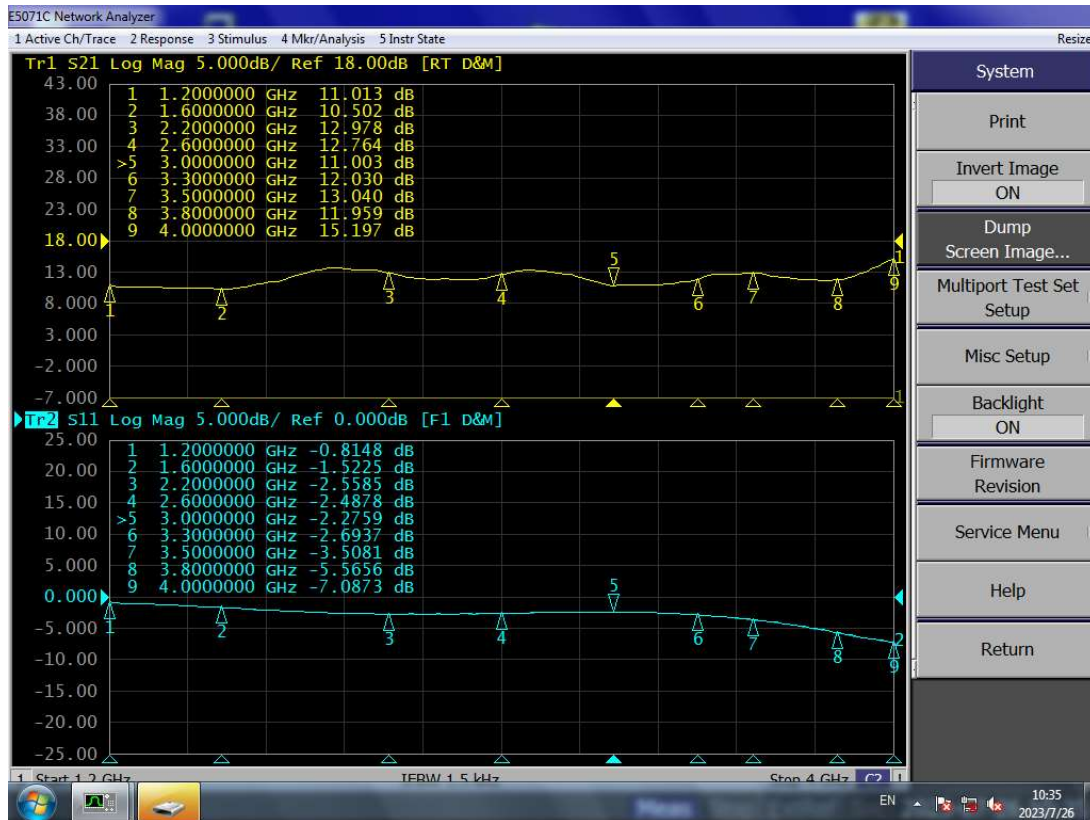
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Table 4. Test Circuit Component Designations and Values

| Component | Description      | Suggestion             |
|-----------|------------------|------------------------|
| C5,C6     | 10uF             | 10uF/100V              |
| C1        | 8.2pF            | MQ101111               |
| C2        | 4.7pF            | MQ101111               |
| C3        | 6.8pF            | MQ101111               |
| C4        | 9.1pF            | MQ101111               |
| C7        | 470uF/63V        | Electrolytic Capacitor |
| R1        | 100 $\Omega$     | Chip Resistor          |
| PCB       | 20Mil Rogers4350 |                        |

Figure 2. Network Analyzer result S11 and S21



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## Package Outline

Flanged ceramic package; 2 leads

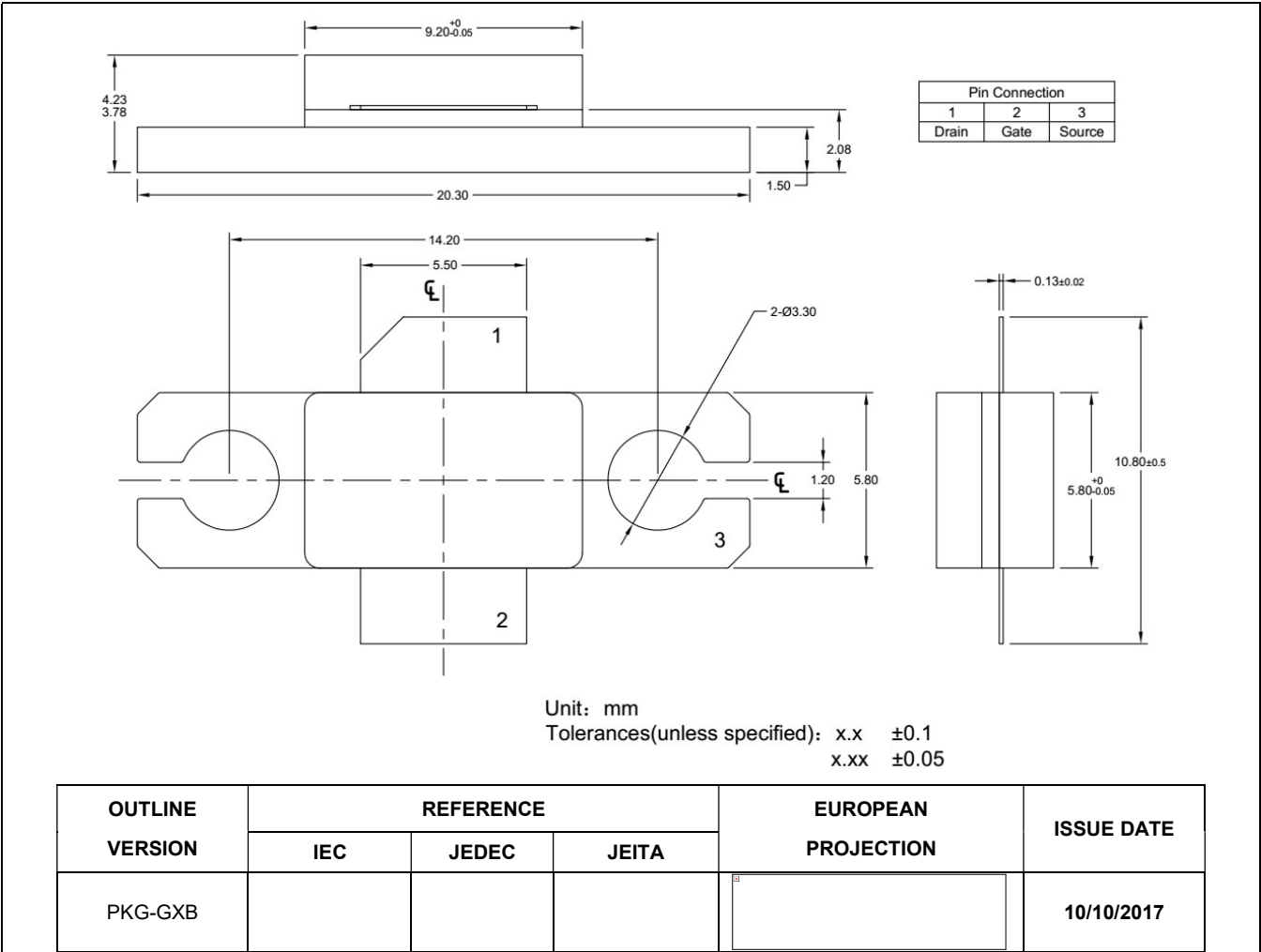


Figure 1. Package Outline PKG-G2E

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## Revision history

Table 4. Document revision history

| Date      | Revision | Datasheet Status  |
|-----------|----------|---|
| 2020/5/13 | V1.0     | Preliminary Datasheet creation                          |
| 2020/7/7  | V1.1     | Correct typo on 1 <sup>st</sup> page                    |
| 2023/7/26 | V2.0     | Use the latest application result, upper limits to 4GHz |

Application data based on YHG-20-11/TC-23-47

## Notice

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